

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

217740US0

SERIAL NO.

NEW APPLICATION

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Hidetoshi YANO, et al.

FILING DATE

HEREWITH

GROUP

2852

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
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	AI						
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
SA	AO	2001-22140	01/26/01	JAPAN (with English Abstract)		X
SA	AP	9-305083	11/28/97	JAPAN (with English Abstract)		X
SA	AQ	8-248820	09/27/96	JAPAN (with English Abstract)		X
	AR					
	AS					
	AT					
	AU					
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	<input type="checkbox"/> Additional References sheet(s) attached

Examiner

Date Considered 10/31/03

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

10/02/03

12/27/01

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

217740US0

SERIAL NO.

10/026,743

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Hidetoshi YANO, et al.

FILING DATE

December 27, 2001

GROUP

2852

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
SA	AO	60-49352	03/18/85	JAPAN (w/English-Abstract)		X
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

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☐ Additional References sheet(s) attached

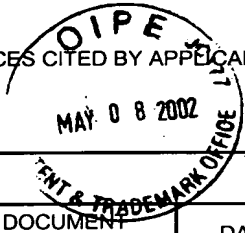
Examiner

A. Lee

Date Considered

10/31/03

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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 217740US0		SERIAL NO. 10/026,743	
LIST OF REFERENCES CITED BY APPLICANT 				APPLICANT Hidetoshi YANO, et al.			
				FILING DATE December 27, 2001		GROUP 2852	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
<i>SL</i>	AA	4,656,966	04/14/87	R. A. GUISTINA			
	AB						
	AC						
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FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO			
<i>SL</i> <i>SL</i> <i>SL</i> <i>SL</i>	AO/	4-287081	12/10/92	JAPAN (with English Abstract)			X
	AP/	2-208685	08/20/90	JAPAN (with English Abstract)			X
	AQ/	61-6678	01/13/86	JAPAN (with English Abstract)			X
	AR/	60-49352	03/18/85	JAPAN (with English Abstract)			X
	AS						
	AT						
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
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Examiner <i>S. Lee</i>				Date Considered 10/31/03			
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December 27, 2001GROUP
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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>SL</i>	AA	6,468,706	10/22/02	MATSUDA, et al.	<i>---</i>	<i>---</i>	
<i>SL</i>	AB	6,492,079	12/10/02	SHIMADA, et al.	<i>---</i>	<i>---</i>	
<i>SL</i>	AC	6,360,068	03/19/02	KINOSHITA, et al.	<i>---</i>	<i>---</i>	
<i>SL</i>	AD	6,500,536	12/31/02	YAMADA, et al.	<i>---</i>	<i>---</i>	
<i>SL</i>	AE	6,395,443	05/28/02	KURODA, et al.	<i>---</i>	<i>---</i>	
<i>SL</i>	AF	6,363,229	03/26/02	SHIRAIISHI, et al.	<i>---</i>	<i>---</i>	
<i>SL</i>	AG	6,403,275	06/11/02	KURAMOTO, et al.	<i>---</i>	<i>---</i>	
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